

<b>Notice of References Cited</b>	Application/Control No. 10/684,981	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0013111	01-2006	Inoue et al.	369/125
*	B	US-2004/0190435	09-2004	Hosoda et al.	369/283
*	C	US-2004/0174804	09-2004	Kakiuchi et al.	369/275.4
*	D	US-2005/0094526	05-2005	Kakiuchi et al.	369/059.11
*	E	US-2004/0139459	07-2004	Mishima et al.	720/718
*	F	US-2004/0174796	09-2004	Mizushima et al.	369/094
*	G	US-2006/0078825	04-2006	Inoue et al.	430/270.12
*	H	US-2005/0243676	11-2005	Kato et al.	369/059.11
*	I	US-2004/0202097	10-2004	Oyake et al.	369/283
*	J	US-2004/0052194	03-2004	Inoue et al.	369/112.23
*	K	US-2004/0157158	08-2004	Kakiuchi et al.	430/270.12
*	L	US-2004/0191685	09-2004	Kakiuchi et al.	430/270.11
*	M	US-2004/0110086	06-2004	Kakiuchi et al.	430/270.12

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	02/29787	04-2002	WIPO	Uno et al.	***
	O	05-342635	12-1993	Japan	***	***
	P	<del>05-234631</del> * 05-342631	12-1993	Japan	Isomura et al.	***
	Q	05-159358	06-1993	Japan	Akiyama et al.	***
	R	03-005929	01-1991	Japan	Sekiya et al.	***
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0152016	08-2004	Mishima et al.	430/270.12
*	B	US-2004/0038080	02-2004	Inoue et al.	428/694.0SC
*	C	US-2004/0027973	02-2004	Aoshima et al.	369/121
*	D	US-2003/0231577	12-2003	Mishima et al.	369/283
*	E	US-2003/0223351	12-2003	Aoshima et al.	369/288
*	F	US-2003/0202452	10-2003	Mishima et al.	369/112.23
*	G	US-2003/0190551	10-2003	Aoshima et al.	430/270.12
*	H	US-2001/0021160	09-2001	Shuy et al.	369/100
*	I	US-6,449,239	09-2002	Uno et al.	369/275.1
*	J	US-2004/0013069	01-2004	Uno et al.	369/59.11
*	K	US-2002/0168587	11-2002	Sakaue et al.	430/270.13
*	L	US-5,328,813	07-1994	Strandjord et al.	430/321
*	M	US-2004/0004932	01-2004	Inoue et al.	369/283

**FOREIGN PATENT DOCUMENTS**

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	N					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,560,998	10-1996	Oyamatsu et al.	428/823.2
*	B	US-2001/0041304	11-2001	UNO et al.	430/270.13
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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